REMARKS

Claims 1, 4-7, 10, 11, 14-17, 19 and 20 were pending in the application.

Claims 1, 4-7, 10, 11, 14-17, 19 and 20 were rejected.

Claim 1 was also objected to.

Claim Objections

The objection to claim 1 has been overcome because the term "being" has been deleted between "...a plurality of test pads electrically" and "connected to..." in line 7 of claim 1, and the phrase "the respective chip pads, the respective test pads," has been deleted between "...for testing electrical properties of the integrated circuits," and "the respective chip pads and test pads being..." in line 8 of claim 1.

Claim Rejections - 35 U.S.C. § 102

Claims 1, 4-7, 10-11, 14-17 and 19-20 are rejected under 35 U.S.C. 102(b) as being anticipated by Aiki, et al. (JP 2002-303653).

Applicant traverses this rejection. Aiki does not teach or suggest the claimed invention for the reasons set forth in detail below.

Claims 1, 4-7, 10-11, 14-17 and 19-20 have been amended to further recite that the respective chip pads and test pads are arranged in each of the first and second pairs of rows. The first pair of rows are arranged substantially parallel to each other and the second pair of rows are arranged substantially parallel to each other. Moreover, the first pair of rows are arranged substantially perpendicular to the second pair of rows. Furthermore, claims 21 and 22 dependent from claims 1 and 11, respectively, have been added. Claims 21 and 22 state that the first set of rows and the second set of rows together form a rectangular configuration.

Thus, the test pads of claims 1, 4-7, 10-11, 14-17 and 19-20 are located within each of the rows in both the first and second set of rows. The first and second set of rows are arranged substantially perpendicular to each other. Therefore, the test pads are in each of the rows are arranged both parallel and perpendicular to each other. In Aiki, the test pads are not present in

each of the rows which are arranged substantially parallel and perpendicular to each other. The test pads are only located in each of the rows which are parallel to each other

Also in Aiki, the test pads are not located within each of the rows of chip pads which are arranged substantially parallel and perpendicular to each other, only in each of the rows which are arranged substantially parallel to each other. The test pads of claims 1, 4-7, 10-11, 14-17 and 19-20, on the other hand, are located within each of the rows of chip pads which are arranged both substantially perpendicular and substantially parallel to each other.

In claims 4 and 14, the test pads are located at the ends of each of the rows of chip pads in each of the first and second set of rows which are arranged both substantially perpendicular and substantially parallel to each other. In Aiki, the test pads are not located within each of the rows of chip pads which are arranged substantially parallel and perpendicular to each other, only in each of the rows which are arranged substantially parallel to each other.

In claims 5 and 15, the configuration of the main circuit area is arranged to form corners, and the test pads are located in each of the first and second pairs of rows, which are arranged both substantially perpendicular and substantially parallel to each other, near the corners of the main circuit area. In Aiki, the test pads are not located near the corners within each of the rows of chip pads which are arranged substantially parallel and perpendicular to each other, only in each of the rows which are arranged substantially parallel to each other

In claims 7 and 17, the test pads are arranged between chip pads within each of the rows of chip pads which are arranged both substantially perpendicular and parallel to each other. In Aiki, the test pads are not arranged between chip pads in each of the rows which are arranged substantially parallel and perpendicular to each other, only in each of the rows which are arranged parallel to each other.

In claims 21 and 22, the first set of rows and the second set of rows together form a rectangular configuration. The test pads are located in each of the first and second pairs of rows, which are arranged both substantially perpendicular and substantially parallel to each other, and

which form the rectangular configuration. In Aiki, the test pads are not arranged between chip pads in each of the rows which form a rectangular configuration that are arranged substantially parallel and perpendicular to each other, only in rows which are arranged parallel to each other.

In order for a prior art reference to anticipate a claim under 35 USC 102 (e), each and every element of the claimed invention must be identically shown in the reference. For the reasons set forth above, the Examiner has not made a prima facie case of anticipation.

For the foregoing reasons, reconsideration and allowance of claims 1, 4-7, 10, 11, 14-17, and 19-22 of the application as amended is requested. The Examiner is encouraged to telephone the undersigned at (503) 222-3613 if it appears that an interview would be helpful in advancing the case.

Respectfully submitted,

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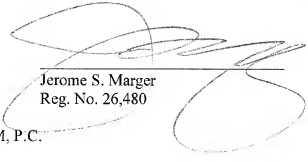

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